

### **Annealing of frozen-in defects in ZnO**

**Nirk, Tiit; Lott, Kalju;** Seeman, Viktor; **Türn, Leo; Viljus, Mart; Öpik, Andres** Physica status solidi (c) 2016 / p. 590-593 : ill  
<https://doi.org/10.1002/pssc.201510244> [Journal metrics at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

### **Effect of ultrasonic treatment on the defect structure of the Si-SiO<sub>2</sub> system**

**Kropman, Daniel;** Seeman, Viktor; Dolgov, Sergei; Medvids, Arturs Physica Status Solidi (C) Current Topics in Solid State Physics 2016 / p. 793 - 797 <https://doi.org/10.1002/pssc.201600052> [Journal metrics at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

### **Stress relaxation mechanism by strain in the Si-SiO<sub>2</sub> system and its influence on the interface properties**

**Kropman, Daniel;** Seeman, Viktor; Dolgov, Sergei; Heinmaa, Ivo; Medvid, Artur Physica Status Solidi (C) Current Topics in Solid State Physics 2016 / p. 790 - 792 <https://doi.org/10.1002/pssc.201600051> [Journal metrics at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

### **Understanding and control of stress at Si-SiO<sub>2</sub> interface**

Kropman, Daniel; Seeman, Viktor; Medvids, Arturs; Onufrijevs, Pavels; Vitusevich, Svetlana; **Mikli, Valdek** Key engineering materials 2020 / p. 291–296 <https://doi.org/10.4028/www.scientific.net/KEM.850.291> [Journal metrics at Scopus](#) [Article at Scopus](#)